



Date Created: 3/1/2004  
Date Issued: 4/27/2004  
PCN # 20040903

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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PCN Type: Die Revision

Effectivity

Expected 1st Device Shipment Date: 7/27/2004  
Earliest Year/Work Week of Changed Product: 0431  
(Note: Package marking may differ from this format)

Product ID (Description):

The products affected by this change are listed below in the "Affected FSIDs" section.

Description of Change:

As part of Fairchild Semiconductor's effort to provide value added products in SO-8, D-pak, and I-pak packages and continue to improve customer service, we are planning to increase cell density to allow a smaller die area while meeting all existing specification limits.

Effect of Change:

No change in the static parametric limits of the data sheet. Based upon final product characterization the power dissipation and thermal resistance values could change for some of the device types in the power package.

Qualification:  
See reliability qual plan below.

Qual/REL Plan Numbers

Additional Qualification Data

**Qual Plan Nbr** : PD02440017  
**Title** : Qualify Process Changes on PT3 Technology  
**Scope** : Applies to PT3 N Channel Fabricated in MTP and SL fabs

**ATTACHMENT 1**  
**RELIABILITY TEST PLAN**

TEST	CONDITION	REL #	13001/9 C1	13001/9 C2	13001/9 C1	Remarks
		DEVICE	FDS6694	FDS6694	FDS6694	
		CHIP	23340FLY	23340FLY	23340FLY	
		PKG	SOP-8	SOP-8	SOP-8	
		DIE LOT#	LD91N	LD91P	LD9A9	
		DURATION	Sample Size	Sample Size	Sample Size	
HTRB	150°C, Vr=80% Bvdss	168hrs	77	77	77	
		500hrs	77	77	77	
		1000hrs	77	77	77	
HTGB	150°C, Vgs=20V	168hrs	77	77	77	
		500hrs	77	77	77	
		1000hrs	77	77	77	
HTRB	175°C, Vr=80% Bvdss	168hrs	77	77	77	
		500hrs	77	77	77	
		1000hrs	77	77	77	
HTGB	175°C, Vgs=20V	168hrs	77	77	77	
		500hrs	77	77	77	
		1000hrs	77	77	77	

Affected FSIDs

FDD6692	FDS4410	FDS6680
FDS6690	FDS6930A	FDU6692